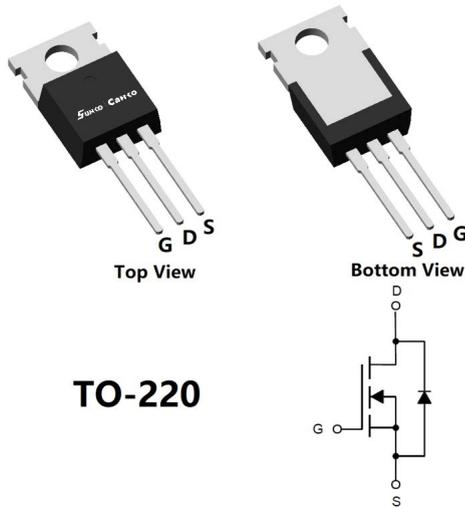


## N-Channel Enhancement Mode Field Effect Transistor



**TO-220**

### Product Summary

- $V_{DS}$  800V
- $I_D$  19A
- $R_{DS(ON)}$  ( at  $V_{GS}=10V$ ) <240m $\Omega$
- 100% EAS Tested
- 100%  $\nabla V_{DS}$  Tested

### General Description

- Excellent package for heat dissipation
- High density cell design for low  $R_{DS(ON)}$
- Epoxy Meets UL 94 V-0 Flammability Rating
- Halogen Free

### Applications

- Power switching application
- Uninterruptible power supply
- DC-DC converter

### Limiting Values

Parameter	Conditions		Symbol	Min	Max	Unit
Drain-source Voltage			$V_{DS}$	-	800	V
Gate-source Voltage			$V_{GS}$	-30	30	
Continuous Drain Current (Note 1,2)	Steady-State	$T_A=25^\circ\text{C}, V_{GS}=10\text{V}$	$I_D$	-	2.4	A
		$T_A=100^\circ\text{C}, V_{GS}=10\text{V}$		-	1.5	
Continuous Drain Current (Note 1,3)	Steady-State	$T_C=25^\circ\text{C}, V_{GS}=10\text{V}, \text{Chip limitation}$		-	19	
		$T_C=100^\circ\text{C}, V_{GS}=10\text{V}$		-	12	
Pulsed Drain Current	$T_C=25^\circ\text{C}, t_p \leq 10\mu\text{s}$		$I_{DM}$	-	45	
Maximum Body-Diode Continuous Current	$T_C=25^\circ\text{C}$		$I_S$	-	19	
Maximum Body-Diode Pulsed Current	$T_C=25^\circ\text{C}, t_p \leq 10\mu\text{s}$		$I_{SM}$	-	45	
Avalanche energy (non-repetitive)	$T_J=25^\circ\text{C}, V_G=10\text{V}, R_G=25\Omega, L=20\text{mH}, I_{AS}=4.5\text{A}$		EAS	-	202.5	mJ
Total Power Dissipation (Note 1,2)	Steady-State	$T_A=25^\circ\text{C}$	$P_D$	-	3.9	W
		$T_A=100^\circ\text{C}$		-	1.5	
Total Power Dissipation (Note 1,3)	Steady-State	$T_C=25^\circ\text{C}$		-	240	
		$T_C=100^\circ\text{C}$		-	96	
MOSFET dv/dt ruggedness	$V_{DS}=0 \dots 400\text{V}, R_G=0\Omega$		dv/dt	-	47.6	V/ns
Reverse diode dv/dt	$V_{DS}=0 \dots 400\text{V}, I_D \leq 15\text{A}, di/dt=200\text{A}/\mu\text{s}$		dv/dt	-	16.6	
Maximum diode commutation speed	$V_{DS}=0 \dots 400\text{V}, I_D \leq 15\text{A}, R_G=0\Omega$		dif/dt	-	7660	A/ $\mu\text{s}$
Junction and Storage Temperature Range			$T_J, T_{STG}$	-55	150	$^\circ\text{C}$

### Thermal resistance

Parameter		Symbol	Typ	Max	Units
Thermal Resistance Junction-to-Ambient (Note 2)	Steady-State	$R_{\theta JA}$	-	32	$^\circ\text{C}/\text{W}$
Thermal Resistance Junction-to-Case	Steady-State	$R_{\theta JC}$	-	0.52	

### Ordering Information (Example)

PREFERRED P/N	PACKING CODE	Marking	MINIMUM PACKAGE(pcs)	INNER BOX QUANTITY(pcs)	OUTER CARTON QUANTITY(pcs)	DELIVERY MODE
SCP210C80BHJ	B1	SCP210C80B	50	/	5000	Tube

## ■ Electrical Characteristics

Parameter	Symbol	Conditions	Min	Typ	Max	Units
<b>Static Parameter</b>						
Drain-Source Breakdown Voltage	$BV_{DSS}$	$V_{GS}=0V, I_D=250\mu A, T_j=25^\circ C$	800	-	-	V
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS}=800V, V_{GS}=0V, T_j=25^\circ C$	-	-	1	$\mu A$
		$V_{DS}=800V, V_{GS}=0V, T_j=150^\circ C$	-	-	100	
Gate-Source Leakage Current	$I_{GSS}$	$V_{GS}=\pm 30V, V_{DS}=0V, T_j=25^\circ C$	-	-	$\pm 10$	$\mu A$
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_D=250\mu A, T_j=25^\circ C$	2.2	3	3.8	V
Static Drain-Source On-Resistance	$R_{DS(on)}$	$V_{GS}=10V, I_D=8.5A, T_j=25^\circ C$	-	200	240	m $\Omega$
		$V_{GS}=10V, I_D=8.5A, T_j=150^\circ C$	-	541	650	
Diode Forward Voltage	$V_{SD}$	$I_S=19A, V_{GS}=0V, T_j=25^\circ C$	-	0.87	1.2	V
Gate resistance	$R_G$	$f=1MHz, T_j=25^\circ C$	-	2.9	-	$\Omega$
<b>Dynamic Parameters</b>						
Input Capacitance	$C_{iss}$	$V_{DS}=400V, V_{GS}=0V, f=1MHz, T_j=25^\circ C$	-	2200	-	pF
Output Capacitance	$C_{oss}$		-	43	-	
Reverse Transfer Capacitance	$C_{rss}$		-	1.9	-	
Effective output capacitance, energy related	$C_{o(er)}$	$V_{DS}=0\dots 400V, V_{GS}=0V, f=1MHz, T_j=25^\circ C$	-	2200	-	pF
Effective output capacitance, time related	$C_{o(tr)}$		-	2210	-	
<b>Switching Parameters</b>						
Total Gate Charge	$Q_g$	$V_{GS}=10V, V_{DS}=400V, I_D=16A, T_j=25^\circ C$	-	48.6	-	nC
Gate-Source Charge	$Q_{gs}$		-	10	-	
Gate-Drain Charge	$Q_{gd}$		-	17.5	-	
Reverse Recovery Charge	$Q_{rr}$	$I_F=16A, di/dt=100A/\mu s, V_{GS}=0V, V_R=400V, T_j=25^\circ C$	-	5713	-	nC
Reverse Recovery Time	$t_{rr}$		-	340	-	ns
Peak Reverse Recovery Current	$I_{rrm}$		-	28.5	-	A
Turn-on Delay Time	$t_{D(on)}$	$V_{GS}=10V, V_{DS}=400V, I_D=16A, R_{GEN}=3\Omega, T_j=25^\circ C$	-	38.6	-	ns
Turn-on Rise Time	$t_r$		-	20.6	-	
Turn-off Delay Time	$t_{D(off)}$		-	43.3	-	
Turn-off fall Time	$t_f$		-	13.2	-	

Note:

- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- The value of  $R_{\theta JA}$  is measured with the device mounted on the 40mm\*40mm\*1.1mm single layer FR-4 PCB board with 1 in<sup>2</sup> pad of 2oz. Copper, in the still air environment with  $T_A=25^\circ C$ . The maximum allowed junction temperature of  $150^\circ C$ . The value in any given application depends on the user's specific board design.
- Thermal resistance from junction to soldering point (on the exposed drain pad)

■ Typical Electrical and Thermal Characteristics Diagrams

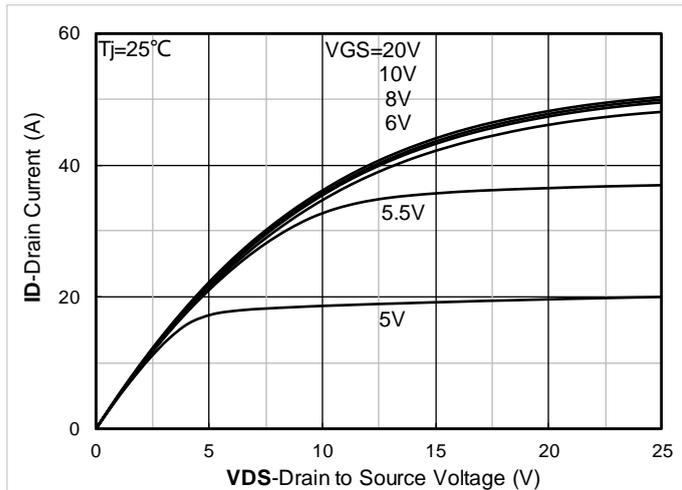


Figure 1. Output Characteristics; typical values

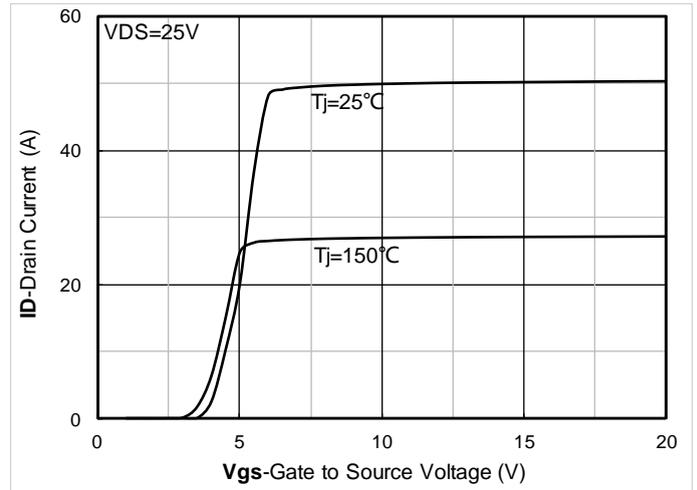


Figure 2. Transfer Characteristics; typical values

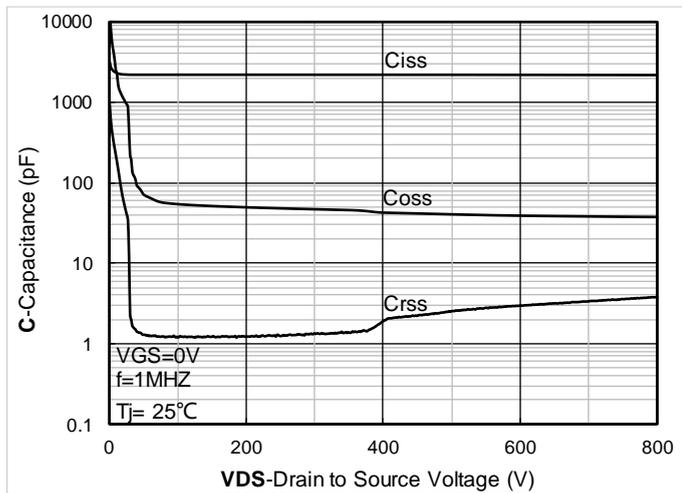


Figure 3. Capacitance Characteristics; typical values

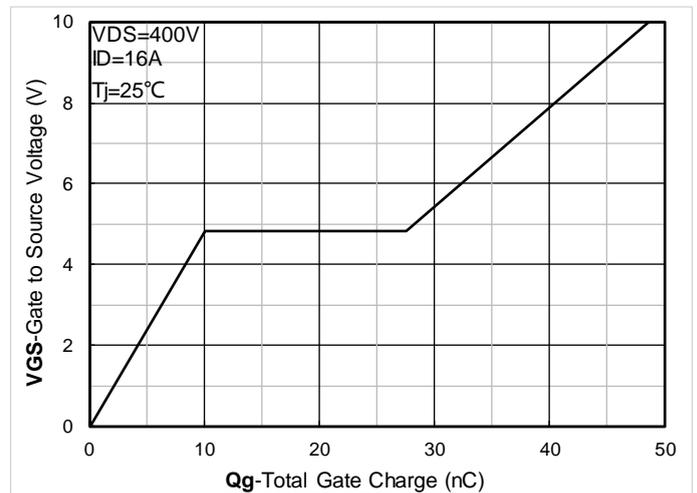


Figure 4. Gate Charge; typical values

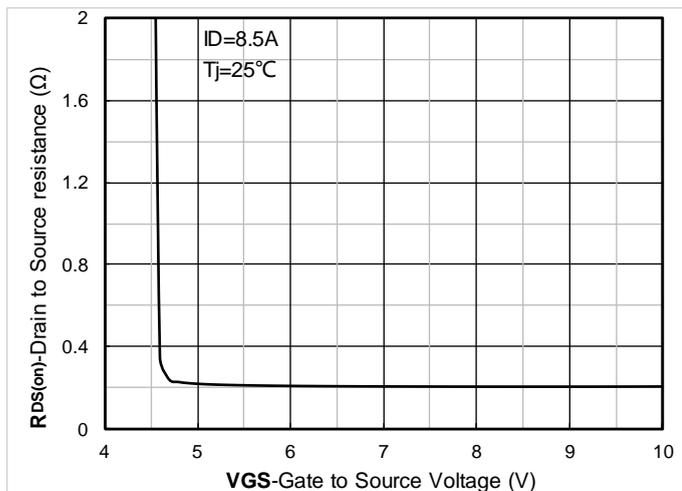


Figure 5. On-Resistance vs Gate to Source Voltage; typical values

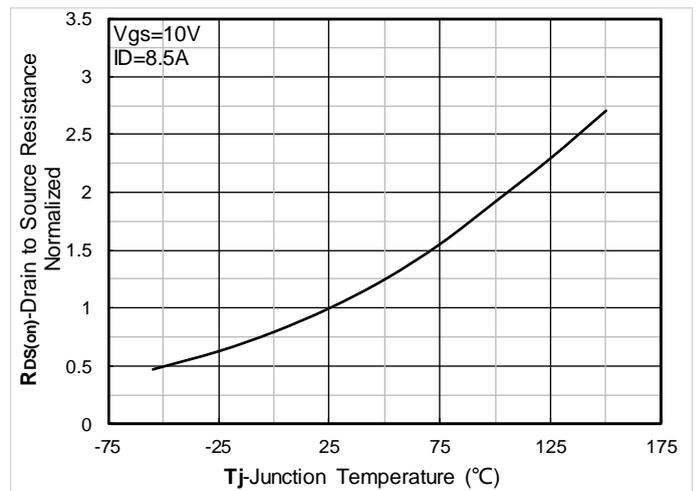


Figure 6. Normalized On-Resistance

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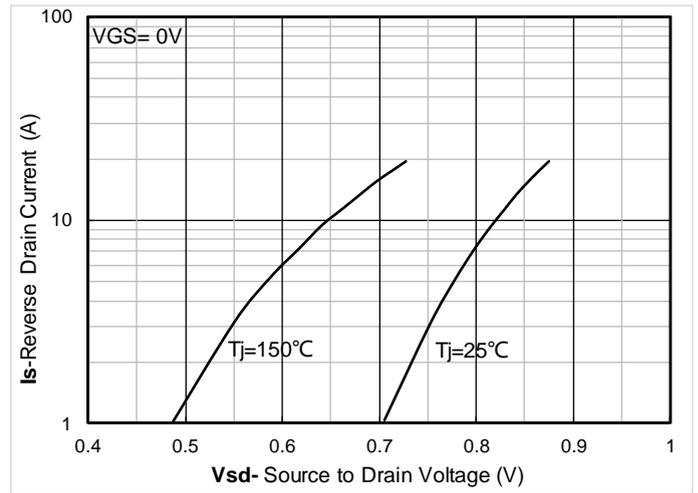
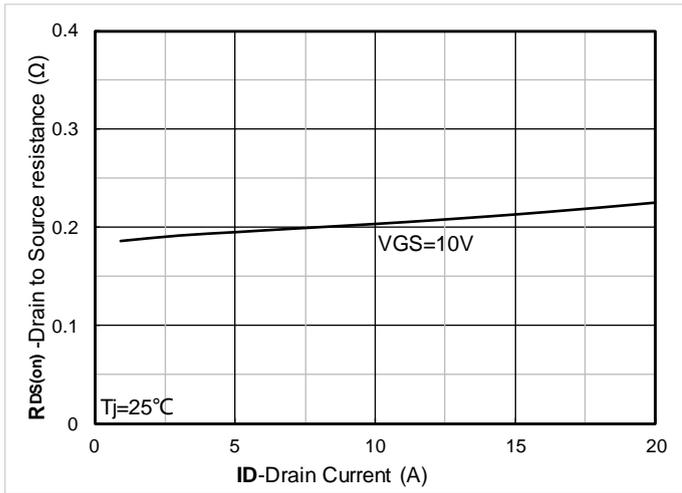


Figure 7. RDS(on) VS Drain Current; typical values

Figure 8. Forward characteristics of reverse diode; typical values

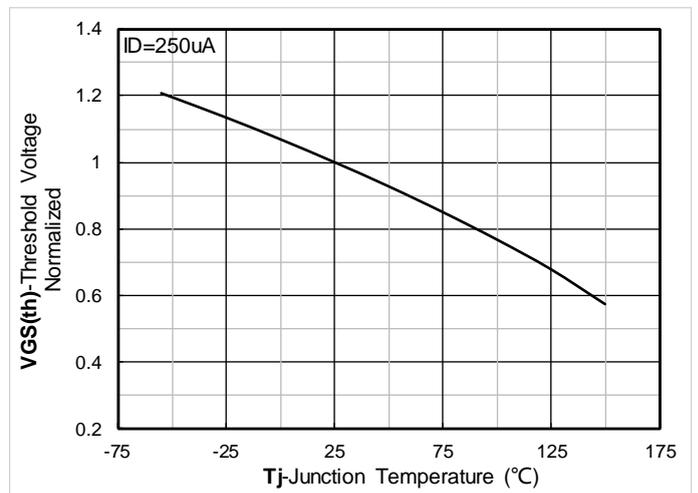
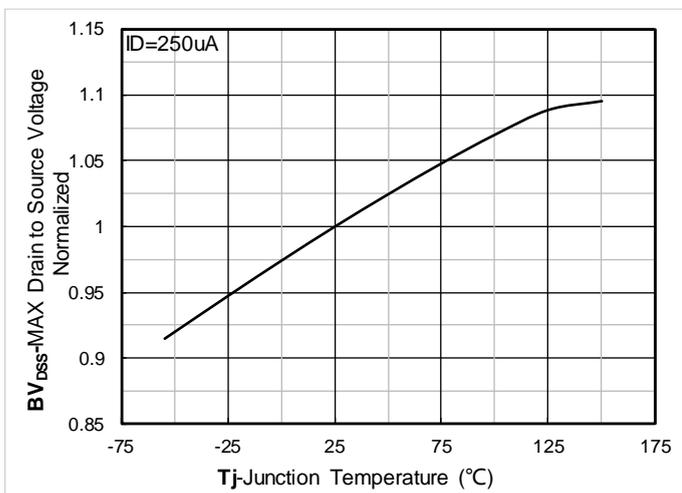


Figure 9. Normalized breakdown voltage

Figure 10. Normalized Threshold voltage

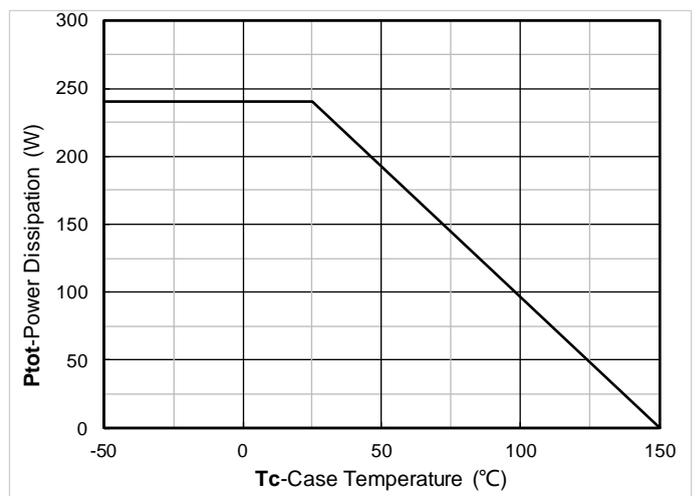
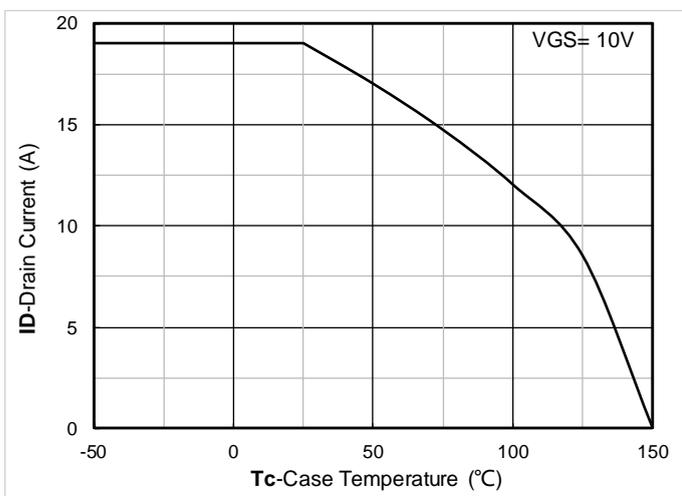


Figure 11. Current dissipation

Figure 12. Power dissipation

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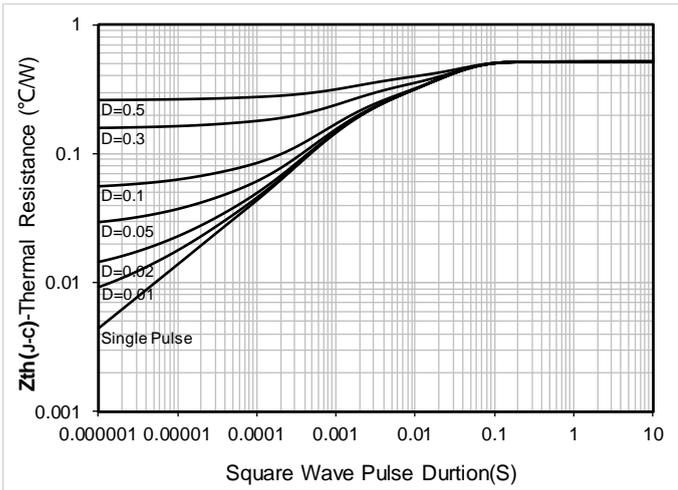


Figure 13. Maximum Transient Thermal Impedance

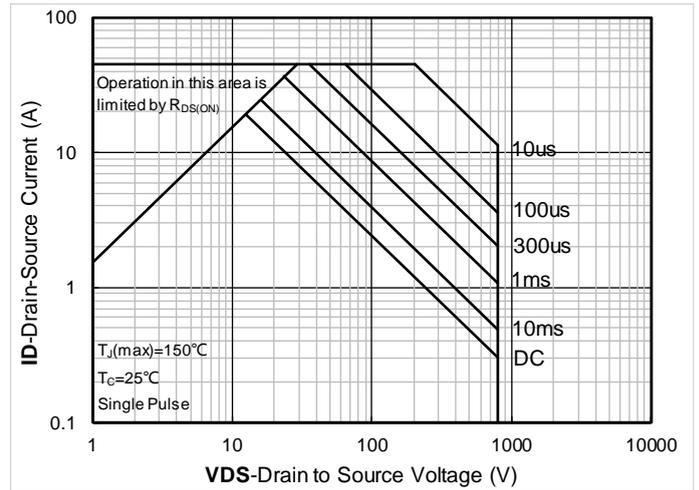


Figure 14. Safe Operation Area

■ Test Circuits & Waveforms

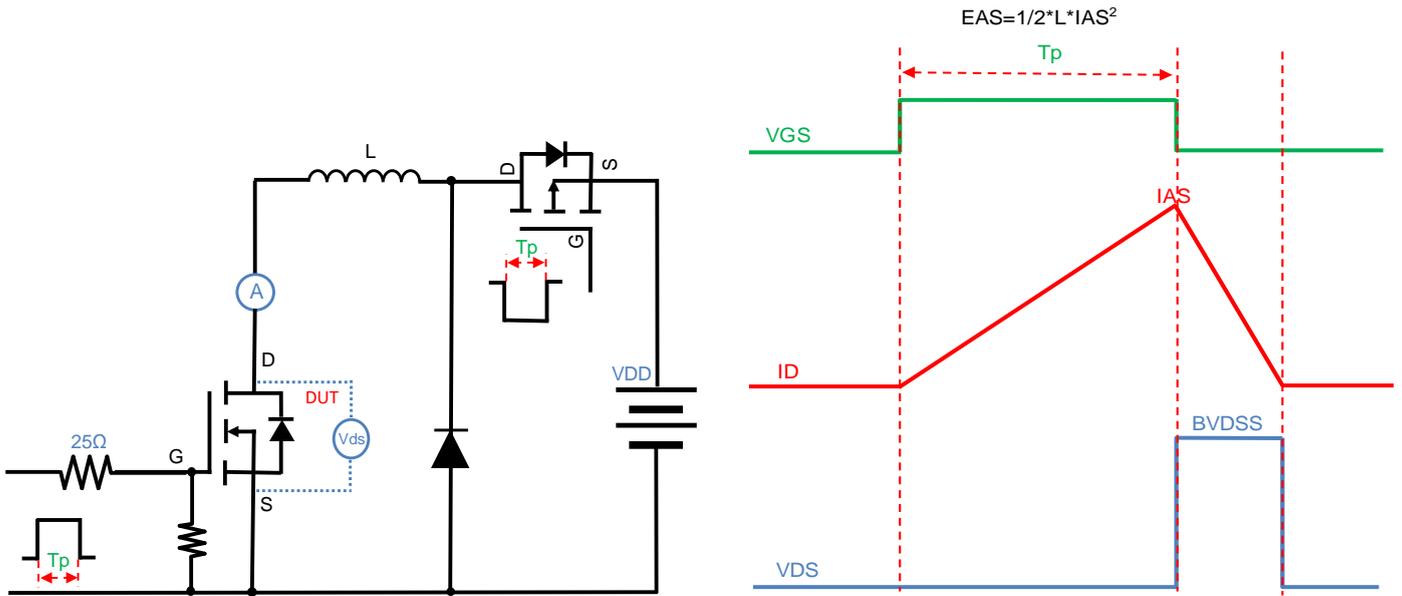


Figure A. Unclamped Inductive Switching (UIS) Test Circuit & Waveform

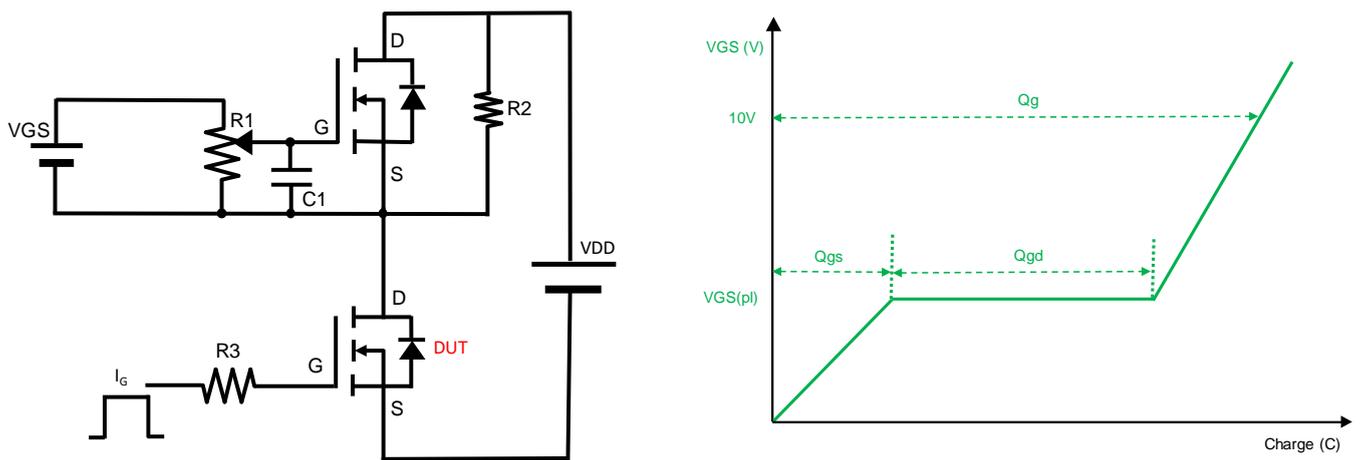


Figure B. Gate Charge Test Circuit & Waveform

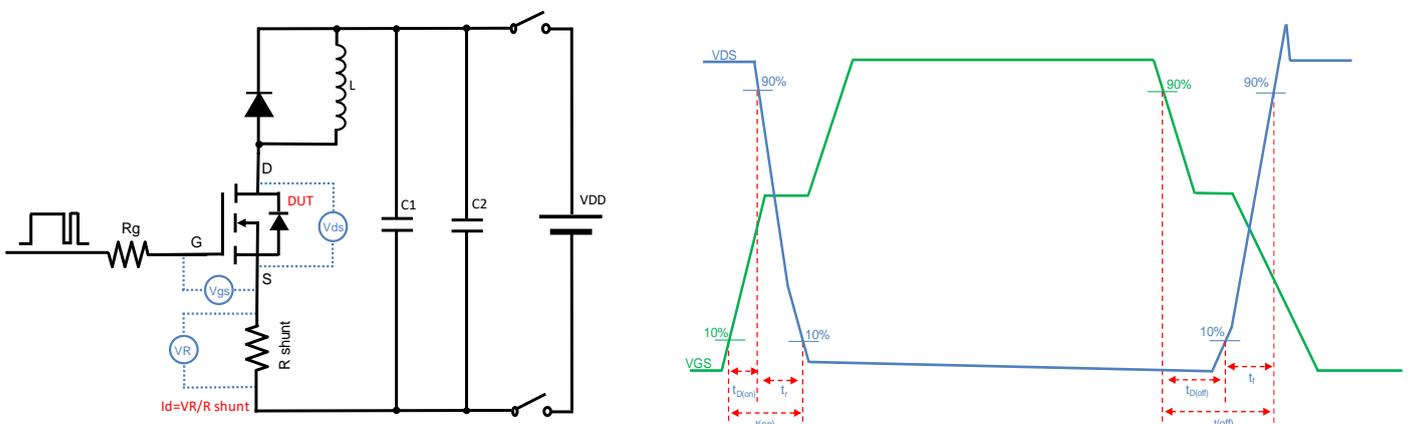


Figure C. Resistive Switching Test Circuit & Waveform

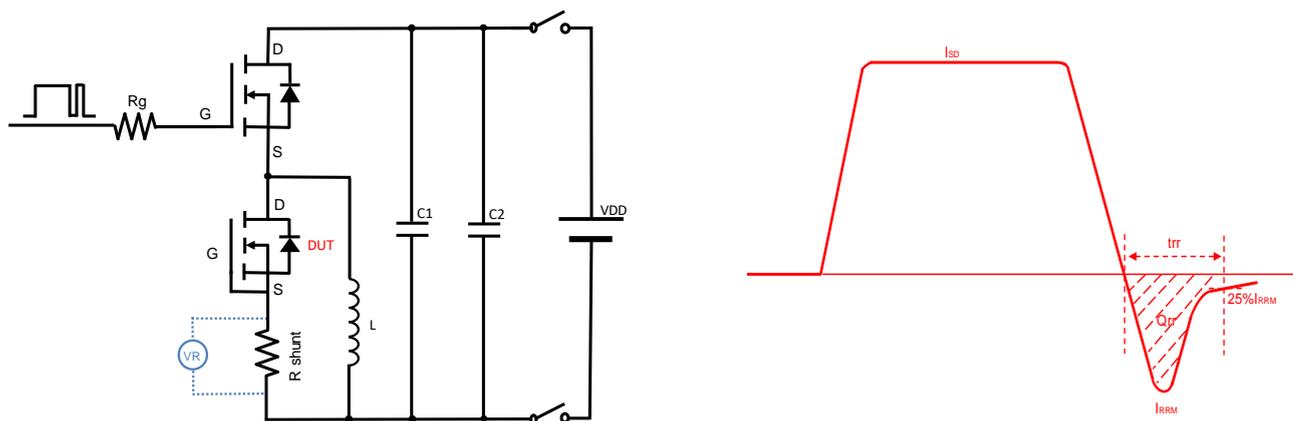
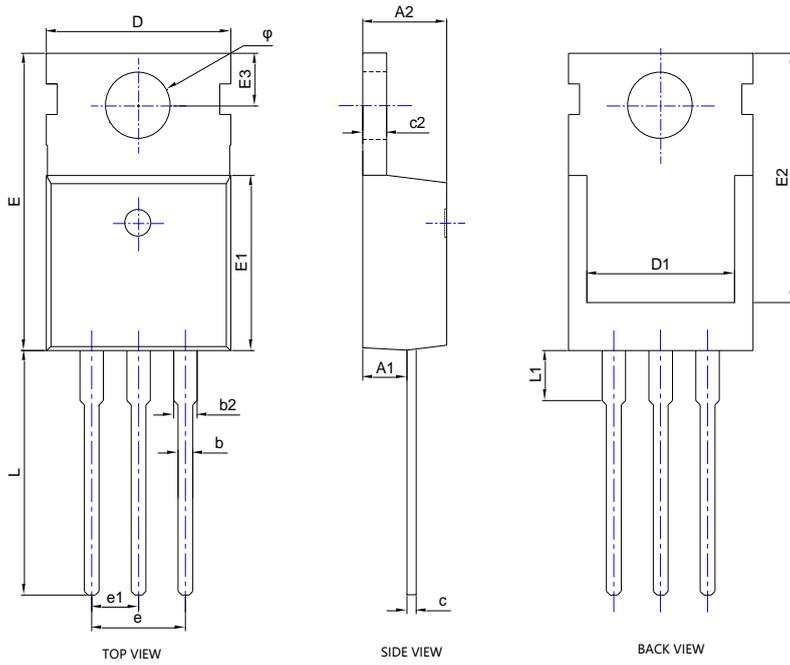


Figure D. Diode Recovery Test Circuit & Waveform

■ TO-220AB-E Package information



SYMBOL	DIMENSIONS			
	INCHES		Millimeter	
	MIN.	MAX.	MIN.	MAX.
A1	0.093	0.114	2.350	2.900
A2	0.176	0.184	4.470	4.670
b	0.028	0.036	0.710	0.910
b2	0.048	0.054	1.220	1.360
c	0.019	0.024	0.470	0.600
c2	0.047	0.055	1.200	1.400
D	0.382	0.408	9.700	10.370
D1	0.276	0.350	7.000	8.890
E	0.579	0.622	14.700	15.800
E1	0.350	0.373	8.900	9.470
E2	0.463	0.535	11.750	13.600
E3	0.108BSC		2.740BSC	
e	0.200BSC		5.080BSC	
e1	0.100BSC		2.540BSC	
L	0.508	0.583	12.900	14.800
L1	0.100	0.151	2.540	3.840
φ	0.142	0.154	3.600	3.900

NOTE:  
 1. PACKAGE BODY SIZES EXCLUDE MOLD FLASH AND GATE BURRS.  
 2. TOLERANCE 0.1mm UNLESS OTHERWISE SPECIFIED.

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